Hybrid 6p209 Traveler

May 15, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 6P209 has die: 152-075 152-076 152-077 152-079 152-080 152-081

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 6p209 classification info. Created 09:48:00 05/04/00

Hybrid 6p209 quality: fair
Chip classification: fair good good good good good
Bad channels: none
Bad cells: none
Random bad capacitors (chip-cell-channel): 0-15-112 0-15-113 0-16-112
   0-16-113 0-2-112 0-2-113 0-28-112 0-28-113 0-4-112 0-4-113 0-41-112
   0-41-113 0-45-112 0-45-113 0-6-112 0-6-113
Channels at pedestal needed for DCMS: 29.7 32.7 30.7 29.5 31.6 31.6
```

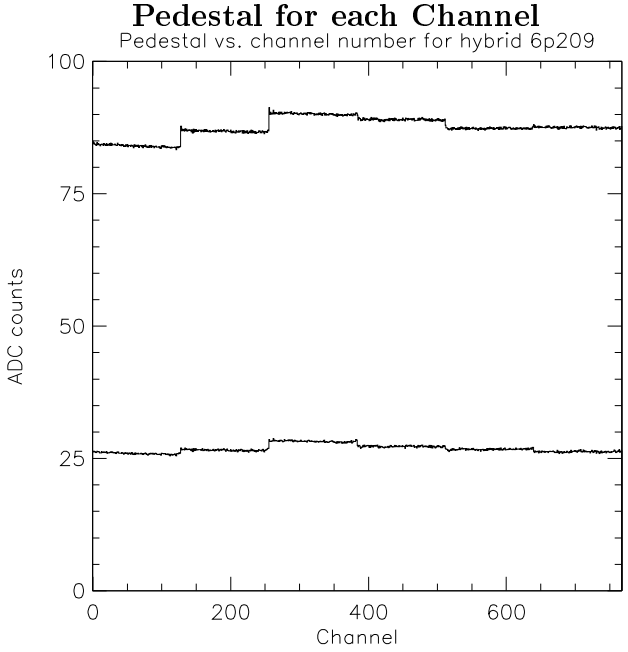
4 Comments

Encapsulated. FE DV finger gold bonds. HV tested.

5 Pedestal

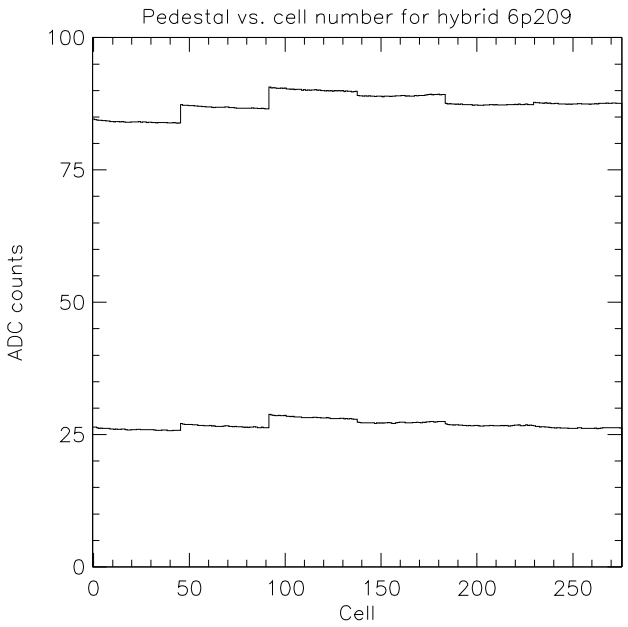
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

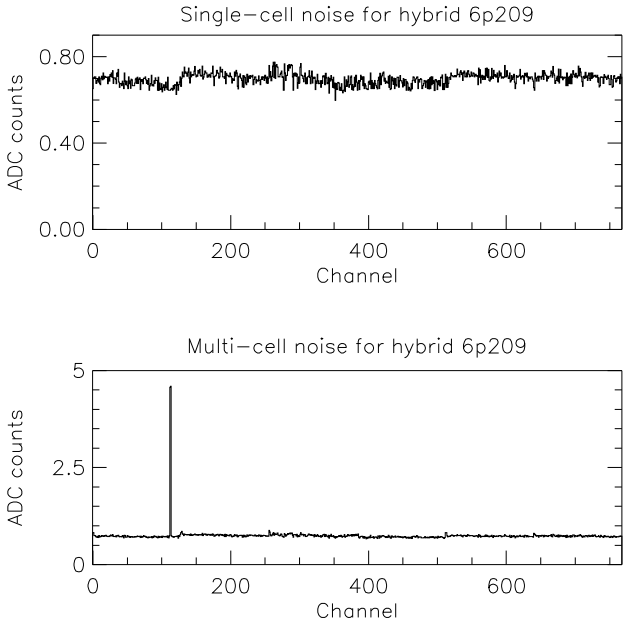
Pedestal vs. Pipeline Cell ID



6 Noise

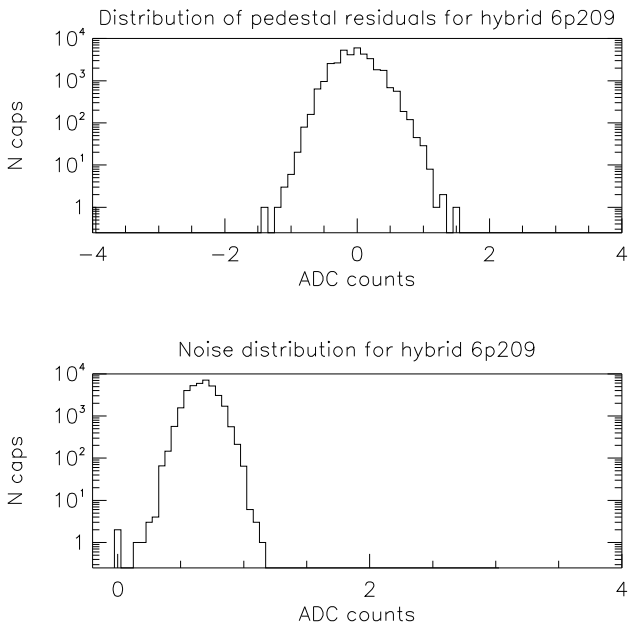
The following plots show the single-cell and multi-cell RMS noise:

RMS Noise

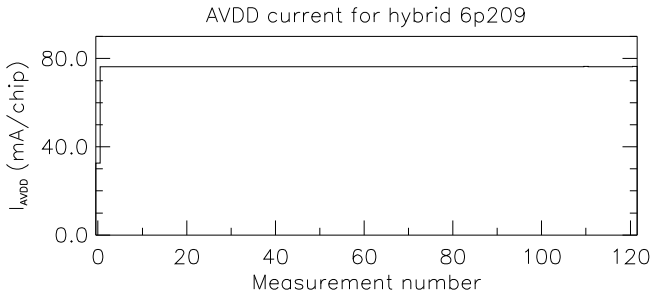
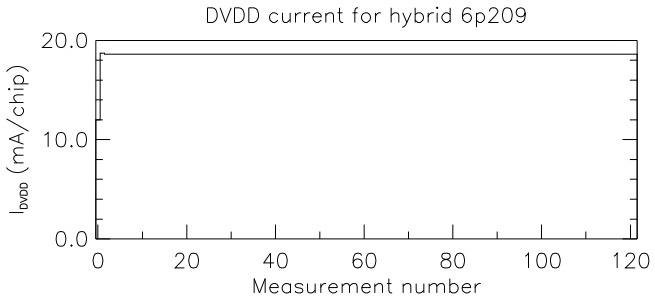


The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise



7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in